## Chunxiang Zhu

## List of Publications by Year in Descending Order

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The third column is the impact factor (IF) of the journal, and the fourth column is the number of citations of the article.

89 3,979 34 62 g-index

101 4,413 5 4.92 ext. papers ext. citations avg, IF L-index

#	Paper	IF	Citations
89	Low Drift Reference-less ISFET Comprising Two Graphene Films with Different Engineered Sensitivities. <i>ACS Applied Electronic Materials</i> , <b>2022</b> , 4, 416-423	4	O
88	Zero-bias mid-infrared graphene photodetectors with bulk photoresponse and calibration-free polarization detection. <i>Nature Communications</i> , <b>2020</b> , 11, 6404	17.4	37
87	Extended Gate Reference-FET (REFET) Using 2D h-BN Sensing Layer for pH Sensing Applications. <i>IEEE Electron Device Letters</i> , <b>2020</b> , 41, 159-162	4.4	5
86	Extended Gate Ion-Sensitive Field-Effect Transistors Using Al2O3/Hexagonal Boron Nitride Nanolayers for pH Sensing. <i>ACS Applied Nano Materials</i> , <b>2020</b> , 3, 403-408	5.6	8
85	Unipolar n-Type Conduction in Black Phosphorus Induced by Atomic Layer Deposited MgO. <i>IEEE Electron Device Letters</i> , <b>2019</b> , 40, 471-474	4.4	6
84	Electronic Devices and Circuits Based on Wafer-Scale Polycrystalline Monolayer MoS2 by Chemical Vapor Deposition. <i>Advanced Electronic Materials</i> , <b>2019</b> , 5, 1900393	6.4	38
83	Artificial Synapses Based on Multiterminal Memtransistors for Neuromorphic Application. <i>Advanced Functional Materials</i> , <b>2019</b> , 29, 1901106	15.6	121
82	Employing a Bifunctional Molybdate Precursor To Grow the Highly Crystalline MoS for High-Performance Field-Effect Transistors. <i>ACS Applied Materials &amp; District </i>	248 <sup>5</sup>	4
81	Waveguide-Integrated Black Phosphorus Photodetector for Mid-Infrared Applications. <i>ACS Nano</i> , <b>2019</b> , 13, 913-921	16.7	96
80	Low-Frequency Noise in Layered ReS Field Effect Transistors on HfO and Its Application for pH Sensing. <i>ACS Applied Materials &amp; amp; Interfaces</i> , <b>2018</b> , 10, 7248-7255	9.5	38
79	Efficient and reliable surface charge transfer doping of black phosphorus via atomic layer deposited MgO toward high performance complementary circuits. <i>Nanoscale</i> , <b>2018</b> , 10, 17007-17014	7.7	27
78	Selectivity of MoS 2 gas sensors based on a time constant spectrum method. <i>Sensors and Actuators A: Physical</i> , <b>2017</b> , 255, 28-33	3.9	14
77	MoS2 based photosensor detecting both light wavelength and intensity. <i>Sensors and Actuators A: Physical</i> , <b>2017</b> , 266, 205-210	3.9	
76	Electrical performance and low frequency noise in hexagonal boron nitride encapsulated MoSe2 dual-gated field effect transistors. <i>Applied Physics Letters</i> , <b>2017</b> , 111, 082105	3.4	16
75	pH Sensing and Low-Frequency Noise Characteristics of Low Temperature (400 °C) p-Channel SOI Schottky ISFETs. <i>IEEE Electron Device Letters</i> , <b>2017</b> , 38, 1146-1149	4.4	9
74	MoS2 oxygen sensor with gate voltage stress induced performance enhancement. <i>Applied Physics Letters</i> , <b>2015</b> , 107, 123105	3.4	21
73	Solution processed F doped ZnO (ZnO:F) for thin film transistors and improved stability through co-doping with alkali metals. <i>Journal of Materials Chemistry C</i> , <b>2015</b> , 3, 1787-1793	7.1	49

## (2008-2015)

72	Orderly Nanopatterned Indium Tin Oxide Electrode Combined with Atomic-Layer-Deposited Metal Oxide Interlayer for Inverted Organic Solar Cells. <i>Energy Technology</i> , <b>2015</b> , 3, 906-912	3.5	4
71	A work-function tunable polyelectrolyte complex (PEI:PSS) as a cathode interfacial layer for inverted organic solar cells. <i>Journal of Materials Chemistry A</i> , <b>2014</b> , 2, 7788-7794	13	42
70	Enhanced inverted organic solar cell performance by post-treatments of solution-processed ZnO buffer layers. <i>RSC Advances</i> , <b>2014</b> , 4, 6646	3.7	34
69	TiOx/Al bilayer as cathode buffer layer for inverted organic solar cell. <i>Applied Physics Letters</i> , <b>2013</b> , 103, 173303	3.4	20
68	Modeling the Negative Quadratic VCC of \$hbox{SiO}_{2}\$ in MIM Capacitor. <i>IEEE Electron Device Letters</i> , <b>2011</b> , 32, 1671-1673	4.4	10
67	A simple and efficient solar cell parameter extraction method from a single current-voltage curve. <i>Journal of Applied Physics</i> , <b>2011</b> , 110, 064504	2.5	172
66	Mechanism investigation and structure design of organic solar cells for improved energy conversion efficiency <b>2010</b> ,		1
65	Effective Surface Passivation by Novel \$hbox{SiH}_{4}\$ \$hbox{NH}_{3}\$ Treatment and BTI Characteristics on Interface-Engineered High-Mobility \$hbox{HfO}_{2}\$ -Gated Ge pMOSFETs. <i>IEEE Transactions on Electron Devices</i> , <b>2010</b> , 57, 1399-1407	2.9	18
64	An Organic-Based DiodeMemory Device With Rectifying Property for Crossbar Memory Array Applications. <i>IEEE Electron Device Letters</i> , <b>2009</b> , 30, 487-489	4.4	12
63	Performance Improvement of \$hbox{Sm}_{2}hbox{O}_{3}\$ MIM Capacitors by Using Plasma Treatment After Dielectric Formation. <i>IEEE Electron Device Letters</i> , <b>2009</b> , 30, 1033-1035	4.4	10
62	Interface-Engineered High-Mobility High-\$k\$ /Ge pMOSFETs With 1-nm Equivalent Oxide Thickness. <i>IEEE Transactions on Electron Devices</i> , <b>2009</b> ,	2.9	22
61	Physical and Electrical Characterization of MetallhsulatorMetal Capacitors With \$hbox{Sm}_{2}hbox{O}_{3}\$ and \$hbox{Sm}_{2}hbox{SiO}_{2}\$ Laminated Dielectrics for Analog Circuit Applications. <i>IEEE Transactions on Electron Devices</i> , <b>2009</b> , 56, 2683-2691	2.9	37
60	Effective Modulation of Quadratic Voltage Coefficient of Capacitance in MIM Capacitors Using \$hbox{Sm}_{2}hbox{O}_{3}/hbox{SiO}_{2}\$ Dielectric Stack. <i>IEEE Electron Device Letters</i> , <b>2009</b> , 30, 460-4	16 <sup>1</sup> 2 <sup>4</sup>	18
59	Enhancement in open circuit voltage induced by deep interface hole traps in polymer-fullerene bulk heterojunction solar cells. <i>Applied Physics Letters</i> , <b>2009</b> , 94, 103305	3.4	21
58	Correction to "An Organic-Based Diode-Memory Device With Rectifying Property for Crossbar Memory Array Applications". <i>IEEE Electron Device Letters</i> , <b>2009</b> , 30, 1218-1218	4.4	11
57	Integration of High-\$kappa\$ Dielectrics and Metal Gate on Gate-All-Around Si-Nanowire-Based Architecture for High-Speed Nonvolatile Charge-Trapping Memory. <i>IEEE Electron Device Letters</i> , <b>2009</b> , 30, 662-664	4.4	7
56	Simple tandem organic photovoltaic cells for improved energy conversion efficiency. <i>Applied Physics Letters</i> , <b>2008</b> , 92, 083310	3.4	59
55	Bistable Electrical Switching and Rewritable Memory Effect in a Thin Film Acrylate Copolymer Containing Carbazole-Oxadiazole Donor Acceptor Pendant Groups. <i>Materials Research Society Symposia Proceedings</i> , <b>2008</b> , 1114, 50201		

54	The use of thermal initiator to make organic bulk heterojunction solar cells with a good percolation path. <i>Applied Physics Letters</i> , <b>2008</b> , 93, 043304	3.4	12
53	Efficient multilayer organic solar cells using the optical interference peak. <i>Applied Physics Letters</i> , <b>2008</b> , 93, 043307	3.4	43
52	Thermally stable polymer memory devices based on a Econjugated triad. <i>Applied Physics Letters</i> , <b>2008</b> , 92, 143302	3.4	45
51	High-k gate stack on germanium substrate with fluorine incorporation. <i>Applied Physics Letters</i> , <b>2008</b> , 92, 163505	3.4	61
50	Effects of fluorine incorporation and forming gas annealing on high-k gated germanium metal-oxide-semiconductor with GeO2 surface passivation. <i>Applied Physics Letters</i> , <b>2008</b> , 93, 073504	3.4	37
49	Polymer electronic memories: Materials, devices and mechanisms. <i>Progress in Polymer Science</i> , <b>2008</b> , 33, 917-978	29.6	860
48	Effect of Gate Dopant Diffusion on Leakage Current in \$ hbox{n}^{+}hbox{Poly-Si}/hbox{HfO}_{2}\$ and Examination of Leakage Paths by Conducting Atomic Force Microscopy. <i>IEEE Electron Device Letters</i> , <b>2007</b> , 28, 373-375	4.4	5
47	Electrically Bistable Thin-Film Device Based on PVK and GNPs Polymer Material. <i>IEEE Electron Device Letters</i> , <b>2007</b> , 28, 107-110	4.4	59
46	Effects of Sulfur Passivation on Germanium MOS Capacitors With HfON Gate Dielectric. <i>IEEE Electron Device Letters</i> , <b>2007</b> , 28, 976-979	4.4	59
45	Reliability analysis of thin HfO2/SiO2 gate dielectric stack <b>2007</b> ,		2
45 44	Reliability analysis of thin HfO2/SiO2 gate dielectric stack <b>2007</b> ,  Polymer memories: Bistable electrical switching and device performance. <i>Polymer</i> , <b>2007</b> , 48, 5182-5201	3.9	195
		3.9	
44	Polymer memories: Bistable electrical switching and device performance. <i>Polymer</i> , <b>2007</b> , 48, 5182-5201  A Comparative Study of \$hbox{HfTaON/SiO}_{2}\$ and \$hbox{HfON/SiO}_{2}\$ Gate Stacks With TaN		195
44	Polymer memories: Bistable electrical switching and device performance. <i>Polymer</i> , <b>2007</b> , 48, 5182-5201  A Comparative Study of \$hbox{HfTaON/SiO}_{2}\$ and \$hbox{HfON/SiO}_{2}\$ Gate Stacks With TaN Metal Gate for Advanced CMOS Applications. <i>IEEE Transactions on Electron Devices</i> , <b>2007</b> , 54, 284-290  Characteristics of Self-Aligned Gate-First Ge p- and n-Channel MOSFETs Using CVD \$hbox{HfO}_{2}\$ Gate Dielectric and Si Surface Passivation. <i>IEEE Transactions on Electron Devices</i> ,	2.9	195 5
44 43 42	Polymer memories: Bistable electrical switching and device performance. <i>Polymer</i> , <b>2007</b> , 48, 5182-5201  A Comparative Study of \$hbox{HfTaON/SiO}_{2}\$ and \$hbox{HfON/SiO}_{2}\$ Gate Stacks With TaN Metal Gate for Advanced CMOS Applications. <i>IEEE Transactions on Electron Devices</i> , <b>2007</b> , 54, 284-290  Characteristics of Self-Aligned Gate-First Ge p- and n-Channel MOSFETs Using CVD \$hbox{HfO}_{2}\$ Gate Dielectric and Si Surface Passivation. <i>IEEE Transactions on Electron Devices</i> , <b>2007</b> , 54, 733-741  A WORM-Type Memory Device with Rectifying Effect Based on a Conjugated Copolymer of PF6Eu	2.9	<ul><li>195</li><li>5</li><li>22</li></ul>
44 43 42 41	Polymer memories: Bistable electrical switching and device performance. <i>Polymer</i> , <b>2007</b> , 48, 5182-5201  A Comparative Study of \$hbox{HfTaON/SiO}_{2}\$ and \$hbox{HfON/SiO}_{2}\$ Gate Stacks With TaN Metal Gate for Advanced CMOS Applications. <i>IEEE Transactions on Electron Devices</i> , <b>2007</b> , 54, 284-290  Characteristics of Self-Aligned Gate-First Ge p- and n-Channel MOSFETs Using CVD \$hbox{HfO}_{2}\$ Gate Dielectric and Si Surface Passivation. <i>IEEE Transactions on Electron Devices</i> , <b>2007</b> , 54, 733-741  A WORM-Type Memory Device with Rectifying Effect Based on a Conjugated Copolymer of PF6Eu on Si Substrate. <i>Materials Research Society Symposia Proceedings</i> , <b>2006</b> , 937, 1  Bi-stable State for WORM Application Based on Carbazole-containing Polymer. <i>Materials Research</i>	2.9	<ul><li>195</li><li>5</li><li>22</li></ul>
44 43 42 41 40	Polymer memories: Bistable electrical switching and device performance. <i>Polymer</i> , <b>2007</b> , 48, 5182-5201  A Comparative Study of \$hbox{HfTaON/SiO}_{2}\$ and \$hbox{HfON/SiO}_{2}\$ Gate Stacks With TaN Metal Gate for Advanced CMOS Applications. <i>IEEE Transactions on Electron Devices</i> , <b>2007</b> , 54, 284-290  Characteristics of Self-Aligned Gate-First Ge p- and n-Channel MOSFETs Using CVD \$hbox{HfO}_{2}\$ Gate Dielectric and Si Surface Passivation. <i>IEEE Transactions on Electron Devices</i> , <b>2007</b> , 54, 733-741  A WORM-Type Memory Device with Rectifying Effect Based on a Conjugated Copolymer of PF6Eu on Si Substrate. <i>Materials Research Society Symposia Proceedings</i> , <b>2006</b> , 937, 1  Bi-stable State for WORM Application Based on Carbazole-containing Polymer. <i>Materials Research Society Symposia Proceedings</i> , <b>2006</b> , 937, 1	2.9	195 5 22 1

## (2003-2006)

36	Non-volatile WORM memory device based on an acrylate polymer with electron donating carbazole pendant groups. <i>Organic Electronics</i> , <b>2006</b> , 7, 173-180	3.5	104
35	Metal-insulator-metal RF bypass capacitor using niobium oxide (Nb2O5) with HfO2/Al2O3 barriers. <i>IEEE Electron Device Letters</i> , <b>2005</b> , 26, 625-627	4.4	29
34	Germanium pMOSFETs with Schottky-barrier germanide S/D, high-/spl kappa/ gate dielectric and metal gate. <i>IEEE Electron Device Letters</i> , <b>2005</b> , 26, 81-83	4.4	82
33	A novel program-erasable high-/spl kappa/ AlN-Si MIS capacitor. <i>IEEE Electron Device Letters</i> , <b>2005</b> , 26, 148-150	4.4	13
32	Study of Germanium Diffusion in HfO2 Gate Dielectric of MOS Device Application. <i>Materials Research Society Symposia Proceedings</i> , <b>2004</b> , 829, 432		1
31	RF, DC, and reliability characteristics of ALD HfO/sub 2/-Al/sub 2/O/sub 3/laminate MIM capacitors for Si RF IC applications. <i>IEEE Transactions on Electron Devices</i> , <b>2004</b> , 51, 886-894	2.9	62
30	Characteristics of high-K spacer offset-gated polysilicon TFTs. <i>IEEE Transactions on Electron Devices</i> , <b>2004</b> , 51, 1304-1308	2.9	22
29	Improvements on surface carrier mobility and electrical stability of MOSFETs using HfTaO gate dielectric. <i>IEEE Transactions on Electron Devices</i> , <b>2004</b> , 51, 2154-2160	2.9	18
28	Schottky-barrier S/D MOSFETs with high-k gate dielectrics and metal-gate electrode. <i>IEEE Electron Device Letters</i> , <b>2004</b> , 25, 268-270	4.4	83
27	Mobility enhancement in TaN metal-gate MOSFETs using tantalum incorporated HfO/sub 2/ gate dielectric. <i>IEEE Electron Device Letters</i> , <b>2004</b> , 25, 501-503	4.4	19
26	Al/sub 2/O/sub 3/-Ge-on-insulator n- and p-MOSFETs with fully NiSi and NiGe dual gates. <i>IEEE Electron Device Letters</i> , <b>2004</b> , 25, 138-140	4.4	45
25	Fully silicided NiSi:Hf-LaAlO/sub 3//SG-GOI n-MOSFETs with high electron mobility. <i>IEEE Electron Device Letters</i> , <b>2004</b> , 25, 559-561	4.4	41
24	A novel self-aligned offset-gated polysilicon TFT using high-/spl kappa/ dielectric spacers. <i>IEEE Electron Device Letters</i> , <b>2004</b> , 25, 194-195	4.4	15
23	A TaN-HfO/sub 2/-Ge pMOSFET with NovelSiH/sub 4/ surface passivation. <i>IEEE Electron Device Letters</i> , <b>2004</b> , 25, 631-633	4.4	99
22	Improvement of voltage linearity in high-/spl kappa/ MIM capacitors using HfO2-SiO2 stacked dielectric. <i>IEEE Electron Device Letters</i> , <b>2004</b> , 25, 538-540	4.4	77
21	Evidence and understanding of ALD HfO2-Al2O3 laminate MIM capacitors outperforming sandwich counterparts. <i>IEEE Electron Device Letters</i> , <b>2004</b> , 25, 681-683	4.4	31
20	Effect of surface NH3 anneal on the physical and electrical properties of HfO2 films on Ge substrate. <i>Applied Physics Letters</i> , <b>2004</b> , 84, 3741-3743	3.4	132
19	Material and Electrical Characterization of HfO2 Films for MIM Capacitors Application. <i>Materials Research Society Symposia Proceedings</i> , <b>2003</b> , 766, 331		

Mim Capacitors with HfO2 and HfAlOx for Si RF and Analog Applications. Materials Research Society 18 Symposia Proceedings, 2003, 766, 591 High-performance MIM capacitor using ALD high-k HfO2-Al2O3 laminate dielectrics. IEEE Electron 17 49 4.4 Device Letters, 2003, 24, 730-732 A high-density MIM capacitor (13 fF/fh2) using ALD HfO2 dielectrics. IEEE Electron Device Letters, 16 108 4.4 2003, 24, 63-65 Physical and electrical characteristics of HfN gate electrode for advanced MOS devices. IEEE 65 15 4.4 Electron Device Letters, 2003, 24, 230-232 MIM capacitors using atomic-layer-deposited high-/spl kappa/ (HfO2)/sub 1-x/(Al2O3)/sub x/ 14 4.4 52 dielectrics. IEEE Electron Device Letters. 2003. 24, 60-62 Fully silicided NiSi and germanided NiGe dual gates on SiO2 n- and p-MOSFETs. IEEE Electron Device 13 22 4.4 Letters, 2003, 24, 739-741 Fully silicided NiSi gate on La2O3 MOSFETs. IEEE Electron Device Letters, 2003, 24, 348-350 12 25 4.4 Very high density RF MIM capacitors (17 fF/h2) using high-/spl kappa/ Al2O3 doped Ta2O5 2.6 11 31 dielectrics. IEEE Microwave and Wireless Components Letters, 2003, 13, 431-433 Physical and electrical characterization of HfO2 metalfhsulatorfhetal capacitors for Si analog 96 10 2.5 circuit applications. Journal of Applied Physics, 2003, 94, 551-557 Lanthanide (Tb)-doped HfO2 for high-density MIM capacitors. IEEE Electron Device Letters, 2003, 24, 442:444 18 9 8 PVD HfO2 for high-precision MIM capacitor applications. IEEE Electron Device Letters, 2003, 24, 387-389 4.4 55 High-density MIM capacitors using AlTaOx dielectrics. IEEE Electron Device Letters, 2003, 24, 306-308 20 4.4 6 A high performance MIM capacitor using HfO2 dielectrics. IEEE Electron Device Letters, 2002, 23, 514-5164.4 78 High density RF MIM capacitors using high-/spl kappa/ AlTaO/sub x/ dielectrics 5 RF passive devices on Si with excellent performance close to ideal devices designed by 23 electro-magnetic simulation Fully silicided NiSi and germanided NiGe dual gates on SiO/sub 2//Si and Al/sub 2/O/sub 13 3//Ge-on-insulator MOSFETs Microwave coplanar filters on Si substrates 4 CVD Polycrystalline Graphene as Sensing Film of Extended-Gate ISFET for Low-Drift pH Sensor. 3.9 2 Journal of the Electrochemical Society,